

	Type	Hits	Search Text
1	BRS	1	((702/75).CCLS.) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit)) AND (interference OR error OR noise)
2	BRS	25	((702/75).CCLS.) AND (interference OR error OR noise) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit) OR IC OR (integrated ADJ circuit))
3	BRS	111	((702/75).CCLS.) AND (interference OR error OR noise)
4	BRS	111	((702/75).CCLS.) AND (interference OR error OR noise OR EMI)
5	BRS	1	((702/75).CCLS.) AND (EMI)
6	BRS	2	((702/75).CCLS.) AND (EMI OR (electromagnetic ADJ interference))
7	BRS	274	probability ADJ variation
8	BRS	15	(probability ADJ variation) AND (noise OR interference OR (error ADJ signal))
9	BRS	379	(probability AND toggle AND delay) AND amplitude
10	BRS	207	((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit) OR IC OR (integrated ADJ circuit))
11	BRS	183	((((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit) OR IC OR (integrated ADJ circuit))) AND correct\$) AND (add OR addition OR sum OR summation)

	Type	Hits	Search Text
12	BRS	101	(((((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit) OR IC OR (integrated ADJ circuit))) AND correct\$) AND (add OR addition OR sum OR summation)) AND node) AND frequency
13	BRS	59	(((((((((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADj integrated ADJ circuit) OR IC OR (integrated ADJ circuit))) AND correct\$) AND (add OR addition OR sum OR summation)) AND node) AND frequency) AND current) AND time) AND (estimat\$3)
14	BRS	3	((((324/95) or (324/501) or (324/612) or (324/750) or (324/751) or (324/765)).CCLS.) AND electromag\$ AND interference AND LSI AND EMI AND correct\$
15	BRS	649	((((702/65) or (702/66) or (702/69) or (702/71) or (702/74) or (702/75) or (702/106) or (702/107) or (702/115) or (702/117) or (702/124) or (702/126) or (702/182) or (702/183) or (702/189) or (702/191) or (702/193) or (702/194) or (702/195)).CCLS.) AND correct\$ AND (add OR addition OR sum OR summation) AND (frequency OR waveform)
16	BRS	42	((((702/65) or (702/66) or (702/69) or (702/71) or (702/74) or (702/75) or (702/106) or (702/107) or (702/115) or (702/117) or (702/124) or (702/126) or (702/182) or (702/183) or (702/189) or (702/191) or (702/193) or (702/194) or (702/195)).CCLS.) AND correct\$ AND (add OR addition OR sum OR summation) AND ((frequency OR waveform) ADJ (analysis OR analyz\$3))

	Type	Hits	Search Text
17	BRS	161	((((702/65) or (702/66) or (702/69) or (702/71) or (702/74) or (702/75) or (702/106) or (702/107) or (702/115) or (702/117) or (702/124) or (702/126) or (702/182) or (702/183) or (702/189) or (702/191) or (702/193) or (702/194) or (702/195)).CCLS.) AND correct\$ AND (add OR addition OR sum OR summation) AND (frequency OR waveform)) AND (LSI OR (large ADJ scale ADJ integrated ADJ circuit) OR IC OR (integrated ADJ circuit))
18	BRS	39	(((((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADJ integrated ADJ circuit) OR IC OR (integrated ADJ circuit))) AND correct\$) AND (add OR addition OR sum OR summation)) AND node) AND frequency) AND current) AND time) AND (estimat\$3)) AND static AND timing AND analysis
19	BRS	93	(((((probability AND toggle AND delay) AND amplitude) AND (interference OR error OR noise OR EMI) AND (LSI OR (large ADJ scale ADJ integrated ADJ circuit) OR IC OR (integrated ADJ circuit))) AND correct\$) AND (add OR addition OR sum OR summation)) AND node) AND frequency) AND current) AND time
20	BRS	7	(probability AND (toggle OR (logic ADJ transition)) AND delay) AND (static ADJ timing ADJ analysis)
21	BRS	1014	probability AND (toggle OR (logic ADJ transition)) AND delay
22	BRS	6	(probability AND toggle AND delay) AND (static ADJ timing ADJ analysis)
23	BRS	974	probability AND toggle AND delay

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- L1: (473) LSI and 324/\$.cccls.
- L2: (2) 1 and EMI
- L3: (16) 1 and hyogo
- L4: (0) 1 and shiga
- L5: (0) 1 and shimazaki
- L6: (4) 1 and kenji
- L7: (2) 1 and kojima
- L8: (0) kenji and shimazaki and 324/\$.cccls.
- L9: (0) kenji and shimazaki and 324/\$.cccls.
- L10: (120) kenji and 324/\$.cccls.
- L11: (59) hirano and 324/\$.cccls.
- L12: (5) 11 and LSI
- L13: (46) 1 and japan
- L14: (65) 1 and correct\$ and waveform\$
- L15: (1) "5521517".PN.
- L16: (1) "5517110".PN.
- L17: (1) "5406209".PN.
- L18: (1) "5028866".PN.
- L19: (123) 1 and analyz\$
- L20: (55) 19 and correct\$
- L21: (24) 20 and waveform\$**

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Default operator: OR

Plurals Synonyms

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20 and waveform\$

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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inventor
1	<input type="checkbox"/>	<input type="checkbox"/>	US 6259244 B1	20010710	60	Electrooptic voltage waveform measuring method	324/96	324/753		Wakana, Shin-ichi, et al.
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6057677 A	20000502	61	Electrooptic voltage waveform measuring method	324/96	324/753		Wakana, Shin-ichi, et al.
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5847570 A	19981208	23	Low jitter trigger circuit for electro-optic probing	324/753	327/113 ; 327/184		Takahashi, Hironor, et al.
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5631555 A	19970520	14	Voltage measurement system	324/96			Takahashi, Hironor, et al.
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5592101 A	19970107	28	Electro-optic apparatus for measuring an electric field	324/753	324/750 ; 324/96		Takahashi, Hironor, et al.
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5504423 A	19960402	12	Method for modeling interactions in multilayered	324/158.1	324/73.1		Fang, Jiayuan
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5436559 A	19950725	22	Method for testing semiconductor device	324/158.1	324/765 ; 714/736		Takagi, Ryoichi, et al.
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5416426 A	19950516	27	Method of measuring a voltage with an electron	324/751			Okubo, Kazuo, et al.
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5412330 A	19950502	19	Optical module for an optically based measurement	324/753	324/96		Ravel, Mihir K., et al.
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5369359 A	19941129	9	Particle beam testing method with countervoltage or	324/158.1	250/310 ; 250/311		Schmitt, Reinhold
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5300880 A	19940405	28	Method of measuring a voltage with an electron	324/751			Okubo, Kazuo, et al.